

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of
OKUNO et al.

Atty. Ref.: 1035-652

Serial No. To be assigned

TC/A.U.: unknown

Filed: August 25, 2006

Examiner: Unknown

For: SAMPLE TARGET HAVING SAMPLE SUPPORT SURFACE WHOSE
FACE IS TREATED, PRODUCTION METHOD THEREOF, AND MASS
SPECTROMETER USING THE SAMPLE TARGET

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August 25, 2006

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

INFORMATION DISCLOSURE STATEMENT

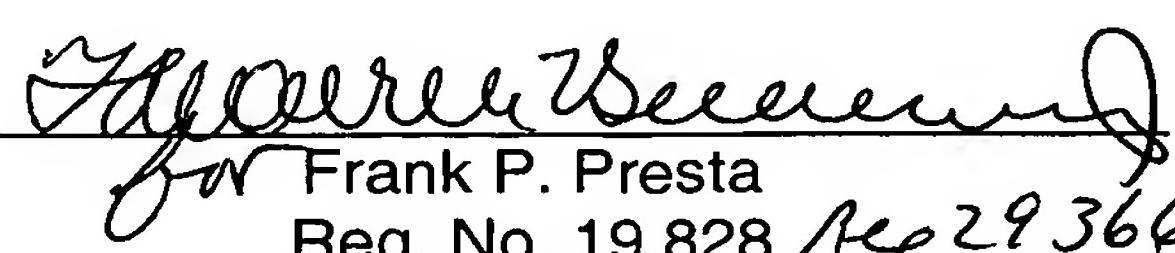
As suggested by 37 C.F.R. 1.97, the undersigned attorney brings to the attention of the Patent and Trademark Office the references listed on the attached form PTO/SB/08a.

This is not to be construed as a representation that a search has been made or that no better prior art exists, or that a reference is relevant merely because cited.

The Examiner is requested to initial the attached form PTO/SB/08a and to return a copy of the initialed document to the undersigned as an indication that the attached references have been considered and made of record.

Respectfully submitted,

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Sheet 1 of 1

IAP12 Rec'd PCT/PTO 25 AUG 2006

INFORMATION DISCLOSURE CITATION	ATTY. DOCKET NO.	SERIAL NO.
	<u>1035-652</u>	<u>10/590822</u>
	APPLICANT	To be assigned
	<u>OKUNO et al.</u>	
(Use several sheets if necessary)	FILING DATE	TC/A.U.
	<u>August 25, 2006</u>	<u>unknown</u>

U.S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

SEARCHED					TRANSLATION	
DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	YES	NO
03/054915 A1	07/2003	WO				
2001-318217	11/2001	JP			ABST	
2004-184137	07/2004	JP				
6-508472	09/1994	JP				
8-189917	07/1996	JP			ABST	

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	International Search Report of PCT/JP2005/003055, mailed 31 May 2005
	“Desorption-Ionization Mass Spectrometry on Porous Silicon”, (Jing WEI et al., Nature, Vol.399, May 1999, pp.243-246)
	“Porous Silicon as a Versatile Platform for Laser Desorption/Ionization Mass Spectrometry”, (Zhouxin SHEN et al., Analytical Chemistry, 73, 2001, pp.612-619)
	“New Desorption Strategies for the Mass Spectrometric Analysis of Macromolecules”, (T. W. HUTCHENS et al., Rapid Communications in Mass Spectrometry, Vol. 7, 1993, pp.576-580)
	“A Self-Assembled Matrix Monolayer for UV-MALDI Mass Spectrometry”, (Stephane Mouradian et al., J. Am. Chem. Soc., 118, 1996, pp.8639-8645)
	“Laser Desorption/Ionization Time-of Flight Mass Spectrometry on Sol—Gel-Derived 2,5-Dihydroxybenzoic Acid Film”, (Ya-Shiuan LIN et al., Analytical Chemistry, Vol. 74, No. 22, November 2002, pp.5793-5798)
	“High Sensitivity and Analyte Capture with Desorption/Ionization Mass Spectrometry on Silylated Porous Silicon”, (Sunia A. TRAUGER et al., Analytical Chemistry, Vol. 76, No. 15, August 12004, pp.4484-4489)
	“Use of a Non-porous Polyurethane Membrane as a Sample Support for Matrix-assisted Laser Desorption/Ionization Time-of-flight Mass Spectrometry of Peptides and Proteins”, (Mark E. McComb et al., Rapid Communications in Mass Spectrometry, Vol. 11, 1997, pp.1716-1722)
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	“UV Laser Desorption/Ionization on Submicrometer Order Structures”, (Shoji OKUNO et al., The 52 nd Annual Conference on Mass Spectrometry, June 2004, pp.118-119, 1-P-34)

*Examiner

Date Considered

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.